

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Makoto IIDA et al.

New U.S. National Phase of PCT/JP2005/000839

Filed: July 25, 2006

Docket No.: 128832

For: A SILICON SINGLE CRYSTAL, A SILICON WAFER, AN APPARATUS FOR  
PRODUCING THE SAME, AND A METHOD FOR PRODUCING THE SAME

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

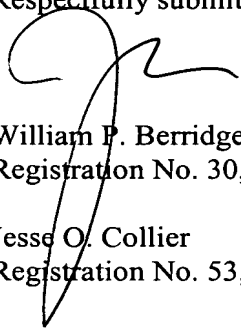
- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. Relevance of one or more non-English language reference is discussed in the present specification. See References 12-15.
- ☒ 3. One or more reference cited herein was cited in the International Search Report. An English language version of the International Search Report is attached for the Examiner's information. See References 3-11.
- ☒ 4. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- ☒ 5. An English language Abstract of one or more non-English language reference is attached hereto. See References 3-15.
- ☒ 6. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office ([<http://www.jpo.go.jp>]), and is attached, but has not been reviewed for accuracy. See References 4-6 and 9-15.

10/586953

New U.S. National Phase of PCT/JP2005/000839  
IAP11 Rec'd PCT/PTO 25 JUL 2006

- ☒ 7. References 1 and 2 correspond to references 3 and 9, respectively.

Respectfully submitted,

  
William P. Berridge  
Registration No. 30,024

Jesse O. Collier  
Registration No. 53,839

WPB:JOC/jdb

Date: July 25, 2006

**OLIFF & BERRIDGE, PLC**  
**P.O. Box 19928**  
**Alexandria, Virginia 22320**  
**Telephone: (703) 836-6400**

<p><b>DEPOSIT ACCOUNT USE AUTHORIZATION</b> Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461</p>
---

10/586953

1.511 Rec'd PCT/PTO 25 JUL 2006

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 128832		New U.S. National Phase of PCT/JP2005/000839	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)				APPLICANTS Makoto IIDA et al.			
				FILING DATE July 25, 2006			
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
	1	5,067,989	11/26/1991	Yokota et al.			
	2	5,609,682	3/11/1997	Sato et al.			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
	3	JP A 03-080193	4/4/1991	Japan	X		
	4	JP A 11-116392	4/27/1999	Japan	X	X	
	5	JP A 2000-327493	11/28/2000	Japan	X	X	
	6	JP A 06-234597	8/23/1994	Japan	X	X	
	7	WO 01/81661 A1	11/1/2001	WIPO	X		
	8	JP A 04-108683	4/9/1992	Japan	X		
	9	JP A 08-073293	3/19/1996	Japan	X	X	
	10	JP A 06-340491	12/13/1994	Japan	X	X	
	11	JP A 09-221381	8/26/1997	Japan	X	X	
	12	JP A 06-016495	1/25/1994	Japan	X	X	
	13	JP A 08-337493	12/24/1996	Japan	X	X	
	14	JP A 10-007488	1/13/1998	Japan	X	X	
	15	JP A 2002-068886	3/8/2002	Japan	X	X	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
	16	Istratov et al.; "Physics of Copper in Silicon;" Journal of the Electrochemical Society Vol. 149, pp. G21-G30, 2002					
EXAMINER					DATE CONSIDERED		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: July 25, 2006